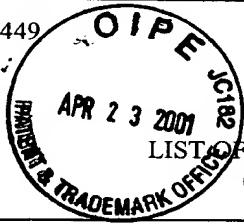


Form 1449

U.S. Department of Commerce  
Patent and Trademark OfficeLIST OF PRIOR ART CITED BY APPLICANT  
(use several sheets if necessary)Docket No.:  
**P01,0008**Serial No.  
**09/762,508**Applicant(s):  
**Joachim Baumann et al.**Filing Date  
**February 7, 2001**Group Art Unit  
**2881****U.S. PATENT DOCUMENTS**

Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If appropriate
GAG	AA	5,206,710	27 April 1993	Geiler et al			
GAG	AB	4,875,175	17 October 1989	Egee et al			
GAG	AC	4,513,384	23 April 1985	Rosencwaig			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
GAG	AJ	DE 196 46 947	14 May 1998	Germany				
GAG	AK	EP 0 735 378	02 October 1996	Europe				
GAG	AL	DE 195 20 788	18 July 1996	Germany				
GAG	AM	DE 42 03 272 A1	12 August 1993	Germany				
GAG	AN	DE 42 03 272 C2	18 May 1995	Germany				
GAG	AO	DE 40 35 266	07 May 1992	Germany				
GAG	AP	DE 36 31 652	24 March 1989	Germany				
GAG	AQ	EP 0 233 120	19 August 1987	Europe				

**OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

GAG	AR	WAGNER, M et al; "Single-beam thermowave analysis of ion implanted and laser annealed semiconductors", Measurement Science & Technology, (1991), Vol. 2, No. 11, Bristol, GB, pgs. 1088-1093.
GAG	AS	WAGNER, M. et al; "Nondestructive Measuring and Testing with Optically Excited Thermal Waves", Laser & Optoelektronik, (1994), Vol. 26, No. 1, pgs. 63-68.
	AT	
	AU	
	AV	
	AW	

Examiner *GAG* Date Considered *6-26-02*  
*ALBERT GAGLIARDI*

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.